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Attorney Docket No. 0553-0401

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Yoshifumi TANADA

Serial No.: 10/807,692

Filed: March 24, 2004

Art Unit:

For: CIRCUIT FOR INSPECTING
SEMICONDUCTOR DEVICE AND INSPECTING METHOD

) I hereby certify that this correspondence
) is being deposited with the United States
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) envelope addressed to:
) Commissioner for Patents, P.O. Box 1450,
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) 2004

Cristie M. Hall

Date: July 29, 2004

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.97, as revised on February 4, 1992, 1135 OG 23-24, Applicant hereby calls the Examiner's attention to documents listed on the attached form, which documents may be material to the examination of this application. Copies of the references are enclosed herewith for the Examiner's consideration.

No inference should be drawn that the attached list sets forth a comprehensive investigation of the prior art, that any or all are pertinent to the invention, or that any apparatus disclosed is equivalent to the subject invention.

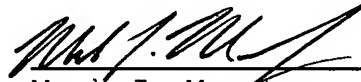
The citation of the above-discussed documents is not to be construed as an assertion that more pertinent art could not possibly be in existence. Citation of any document herein is not to be construed as an admission that any subject matter disclosed

in the document is necessarily within the inventive field of endeavor, that any disclosure is necessarily prior in time to a particular date which may be relevant to the instant patent application, and/or that any disclosure is otherwise necessarily prior art with respect to the instant invention.

Applicant also respectfully reserves the right to later set forth how the instant invention is distinguished over the disclosure of any document or other art, including the disclosure of those documents discussed herein, that may be cited by the Examiner in rejecting a claim in the instant patent application.

The references disclosed herein were cited in an international search report dated April 27, 2004, in a counterpart PCT application. An English translation of an opinion filed in the counterpart PCT application dated April 27, 2004, is also being submitted herewith. A first Office Action, Notice of Allowance or Issue Fee has not been received in this case, so Applicant does not believe that a fee is due. However, if any such fee is required, please charge our Deposit Account No. 50/1039.

Respectfully submitted,



Mark J. Murphy
Registration No.: 34,225

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LIST OF PUBLICATIONS
CITED BY APPLICANT

Atty Docket No.
0553-0401

Serial No.
10/807,692

Applicant
Yoshifumi TANADA

Filing Date
March 24, 2004

Group

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB- CLASS | FILING DATE |
|----------------------|--------------------|------|------|-------|---------------|----------------|
| | | | | | | |

FOREIGN PATENT DOCUMENTS

| | DOCUMENT NUMBER | DATE | APPLICANT | English Abstract | English Trans. | FILING DATE |
|--|--------------------|----------|-------------------------------------|---------------------|-------------------|----------------|
| | JP 05-256914 | 10/08/93 | Toshiba Corp. | X | | 03/12/92 |
| | JP 2000-047255 | 02/18/00 | Matsushita Elect. Ind. Co., Ltd. | X | | 07/27/98 |

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

(Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).

- 1) International Search Report for application no. PCT/JP2004/003549, dated April 27, 2004 (In Japanese).
- 2) Written opinion for application no. PCT/JP2004/003549, dated April 27, 2004 (with partial English translation).

EXAMINER:

DATE CONSIDERED:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP form. Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.